Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/533,830	VOGT ET AL.	
Examiner	Art Unit	
lafar Parea	1621	

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	SEARCHED				
Class	Subclass	Date	Examiner		
518	700, 715, 719	1/22/2007	JP		
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INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East, STN	1/22/2007	JP
inventor name search	1/22/2007	JP
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